

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/723,389 | | Applicant(s)/Patent Under Reexamination VEARIEL ET AL. | |
| | Examiner DIMPLE N. BODAWALA | | Art Unit 1791 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-3,521,325 A | 07-1970 | SCHIPPERS HEINZ | 425/3 |
| * | B | US-3,819,777 A | 06-1974 | L. Vermeerbergen | 264/40.6 |
| * | C | US-4,184,832 A | 01-1980 | Cuff, David W. | 425/308 |
| * | D | US-5,192,543 A | 03-1993 | Irvin et al. | 425/378.1 |
| * | E | US-6,220,847 B1 | 04-2001 | Yoshida et al. | 425/313 |
| * | F | US-6,474,969 B1 | 11-2002 | Ready et al. | 425/67 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.